

EAST - (10646320.wsp.1)

File View Edit Tools Window Help

Save

S1: (746) (test\$4) near5 plurality adj3 ((integ
S2: (882) (test\$4 or detect\$4 or measur\$4) near
S3: (6017) 324/765, "158""."."1".ccls.
S4: (190) (((test\$4 or detect\$4 or measur\$4) nea
S5: (49) (((test\$4 or detect\$4 or measur\$4) nea
S6: (8) test\$4 near5 (plurality adj (integrated
S7: (2) test\$4 near5 (plurality adj (integrated
S8: (10132) 324/754-765.ccls.
S9: (251) ((test\$4) near5 plurality adj3 ((inte
S10: (519691) control\$4 near5 switch
S11: (125) ((test\$4 or detect\$4 or measur\$4) ne
S12: (608) 324/760.ccls.
S13: (2) (control\$4 near5 switch) and (((test\$
S14: (36) ((test\$4) near5 plurality adj3 ((inte
S15: (55931) (test\$4 or detect\$4) near5 ((integ
S16: (564521) control\$4 near5 (switch or relay)
S17: (5431) ((test\$4 or detect\$4) near5 ((integ
S18: (8671) 324/765,760,158.1.ccls.
S19: (306) (((test\$4 or detect\$4) near5 ((integ
S20: (4) ("5794175" | "5969537" | "6297659" | "
S21: (1745) (test\$4 or detect\$4) near5 ((integr
S22: (0) ((test\$4 or detect\$4) near5 ((integrat
S23: (147) ((test\$4 or detect\$4) near5 ((integr
S24: (44) (((test\$4 or detect\$4) near5 ((integr
S25: (126283) logic adj circuit

US-PCPUB USPAT EPO JPO DERVENT GW TOB

Default operator OR

Highlight all hit terms initially

BR form IS&R form Image Text HTML

U	1	Document ID	Issue Dat	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	3	4
1	<input type="checkbox"/>	US 4263669	19810421	7	Pattern generation system	714/744			Staiger; Dieter E.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2	<input type="checkbox"/>	US 5289116	19940222	12	Apparatus and method for testing electronic	324/76.11	324/73.1		Kurita; Jun et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3	<input type="checkbox"/>	US 5389556	19950214	45	Individually powering-up unsingulate	438/17	148/DIG.28		Rostoker; Michael D. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4	<input type="checkbox"/>	US 5391984	19950221	6	Method and apparatus for testing integrated	324/158.1	324/73.1;		Worley; James L.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
5	<input type="checkbox"/>	US 5794175	19980811	13	Low cost, highly parallel memory tester	702/119	324/158.1;		Conner; George W.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
6	<input type="checkbox"/>	US 5929650	19990727	18	Method and apparatus for performing operativ	324/763	324/765;		Pappert; Bernard J. et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
7	<input type="checkbox"/>	US 5929651	19990727	18	Semiconductor wafer test and burn-in	324/765	714/25		Leas; James Marc et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8	<input type="checkbox"/>	US 6057698	20000502	9	Test system for variable selection of	324/765	324/760		Heo; Kyeong Il et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9	<input type="checkbox"/>	US 6087190	20000711	14	Automatic test process with non volatile mem	438/11	438/18		Wan; Ray-Lin et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

Hits Details HTML

Ready

NUM